Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/766,696	FUJII, KAZUHIRO	
Examiner	Art Unit	

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Anne Marie M. Boehler

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Class	Subclass	Date	Examiner
280	288.4		
	260, 261		
180	205		
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	207		
474	80, 81		
	110,144		
248	200,230.1		
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INTERFERENCE SEARCHED				
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